

# Uncertainty Quantification for Emulators

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# Emulators, Surrogate functions, Metamodels

Common to approximate “expensive” functions from few values.  
Expense computational or real (e.g., experiment).

- Kriging
- Multivariate Adaptive Regression Splines (MARS)
- Projection Pursuit Regression
- Polynomial Chaos Expansions
- Gaussian process models (GP)
- Neural networks
- etc.

# Noiseless non-parametric function estimation

- True  $f$  infinite-dimensional, on possibly high-dimensional domain.
- Observe only  $n$  samples from  $f$ .
- Estimating  $f$  is grossly underdetermined problem.
- Usual context is scientific problem involving values of  $f$  where it was not observed.

## Common context

Part of larger problem in uncertainty quantification (UQ):

- Real-world phenomenon
- Physics description of phenomenon
- Theoretical simplification/approximation of the physics
- Numerical solution of the approximation  $f$
- Emulation of the numerical solution of the approximation  $\hat{f}$
- Calibration to noisy data
- “Inference”

## HEB Models

High dimensional domain, Expensive, Black-box.

- Climate models (Covey et al., 2011: 21–28-dimensional domain 1154 simulations, Kriging and MARS)
- Car crashes (Aspenberg et al., 2012: 15-dimensional domain; 55 simulations; polynomial response surfaces and neural networks).
- Chemical reactions (Holena et al., 2011: 20–30-dimensional domain, boosted surrogate models; Shorter et al., 1999: 46-dimensional domain)
- Aircraft design (Srivastava et al., 2004: 25-dimensional domain, 500 simulations, response surfaces and Kriging; Koch et al., 1999: 22-dimensional domain, minutes per run, response surfaces and Kriging; Booker et al., 1999: 31-dimensional domain, minutes to days per run, Kriging).
- Electric circuits (Bates et al., 1996: 60-dimensional domain; 216 simulations; Kriging).

## How accurate are emulators?

- High-consequence decisions are made on the basis of emulators.
- How accurate are they in practice?
- How can the accuracy be estimated reliably, measured or bounded?
- How many training data are needed to ensure that an emulator is accurate?

## Common strategies

- For Bayesian emulators, common to use the posterior distribution to measure uncertainty (Tebaldi & Smith, 2005)
- Also common to measure error using observations not used to train the emulator (Fang et al., 2006)
- Required conditions generally cannot be verified or known to be false.
- Posterior depends on prior and likelihood, but inputs are generally fixed parameters, not random.
- Validation on hold-out observations relevant if the error at the held-out observations is representative of the error everywhere. Observations not usually IID; values of  $f$  not IID.

## Constraints are key

- Without constraints on  $f$ , no reliable way to extrapolate to values of  $f$  at unobserved inputs: completely indeterminate.
- Need  $f$  to have some kind of regularity; does not typically come from the problem.
- Uncertainty estimates are driven by assumptions about  $f$ .
- Stronger assumptions  $\rightarrow$  smaller uncertainties.
- What do the data justify?
- How can we avoid foolhardy optimism?



## Lipschitz bound

Use absolute condition number aka Lipschitz constant:

Given a metric  $d$  on  $\text{dom}(g)$ , best Lipschitz constant  $K$  for  $g$  is

$$K(g) \equiv \sup \left\{ \frac{g(v) - g(w)}{d(v, w)} : v, w \in \text{dom}(g) \text{ and } v \neq w \right\}. \quad (1)$$

If  $f \notin \mathcal{C}[0, 1]^p$ , then  $K(f) \equiv \infty$ .

## What's the problem?

- If we knew  $f$ , we could emulate it perfectly—by  $f$ .
- Require emulator  $\hat{f}$  to be computable from the observations, without relying on any other information about  $f$ .
- If we knew that the Lipschitz constant of  $f$  is  $K$ , could guarantee of some level of accuracy.
- All else equal, the larger  $K$  is, the more difficult it is to guarantee that an approximation of  $f$  is accurate.

## What do we know about $K$ ?

Observations  $f|_{\mathcal{X}}$  impose a lower bound on  $K$  (but no upper bound).

$\exists \hat{f}$ , computable from the data  $f|_{\mathcal{X}}$ , guaranteed to be accurate throughout the domain of  $f$ —no matter what  $f$  is—provided  $f$  agrees with the observations  $f|_{\mathcal{X}}$  and has a Lipschitz constant not greater than the observed lower bound on  $K$ ?

# Minimax formulation: Information-Based Complexity

- potential error: minimax error of emulators over the set  $\mathcal{F}$  of functions that agree with data & have Lipschitz constant no greater than the lower bound, as function over  $\text{dom}(f)$
- maximum potential error: supremum of potential error over  $\text{dom}(f)$
- For known  $K$ , finding potential error is standard problem in information-based complexity.
- $K$  is unknown since  $f$  is only partially observed. We bound potential error using a lower bound for  $K$  computed from data.

## Sketch of results

- Lower bound on number of additional observations possibly necessary to “learn”  $f$  w/i  $\epsilon$ .
- Application to Community Atmosphere Model:  $n$  required could be astronomical.
- Two lower bounds on the maximum potential error for approximating  $f$  from a fixed set of observations: empirical, and as a fraction of the unknown  $K$ .
- Conditions under which a constant emulator has smaller maximum potential error than best emulator trained on the actual observations. Conditions hold for the CAM simulations.
- Use sampling to estimate quantiles and mean of the potential error across the domain. For CAM, moderate quantiles are a large fraction of maximum.

## Notation and problem formulation

$f$ : fixed unknown real-valued function on  $[0, 1]^p$

$\mathcal{C}[0, 1]^p$ : real-valued continuous functions on  $[0, 1]^p$

$\text{dom}(g)$ : domain of function  $g$

$g|_D$ : restriction of  $g$  to  $D \subset \text{dom}(g)$

$f|_X$ : data, observations of  $f$  on  $X$

$\hat{f}$ : emulator based on  $f|_X$ , but no other information about  $f$

$\|h\|_\infty \equiv \sup_{w \in \text{dom}(h)} |h(w)|$

$d$ : a metric on  $\text{dom}(g)$

$K(g)$ : best Lipschitz constant for  $f$

$$\mathcal{F}_\kappa(g) \equiv \{h \in \mathcal{C}[0, 1]^P : K(h) \leq \kappa \text{ and } h|_{\text{dom}(g)} = g\}.$$

$\mathcal{F}_\infty(f|_X)$  is the space of functions in  $\mathcal{C}[0, 1]^P$  that fit the data.

potential error of  $\hat{f} \in \mathcal{C}[0, 1]^P$  over the set of functions  $\mathcal{F}$ :

$$\mathcal{E}(w; \hat{f}, \mathcal{F}) \equiv \sup \left\{ |\hat{f}(w) - g(w)| : g \in \mathcal{F} \right\}.$$

maximum potential error of  $\hat{f} \in \mathcal{C}[0, 1]^P$  over the set of functions  $\mathcal{F}$ :

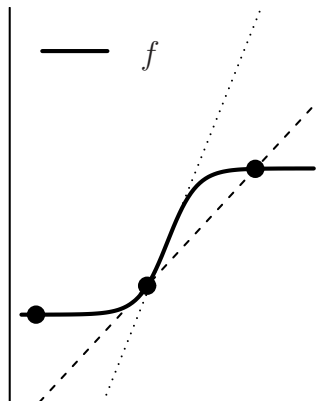
$$\mathcal{E}(\hat{f}, \mathcal{F}) \equiv \sup_{w \in [0, 1]^P} \mathcal{E}(w; \hat{f}, \mathcal{F}) = \left\{ \|\hat{f} - g\|_\infty : g \in \mathcal{F} \right\}.$$

## Maximum potential error

- Example of worst-case error in IBC.
- The uncertainty  $\hat{f}$  is  $\mathcal{E}(\hat{f}, \mathcal{F}_\infty(f|_X))$ .
- Presumes  $f \in \mathcal{C}[0, 1]^p$ .
- If  $f \notin \mathcal{C}[0, 1]^p$ ,  $\hat{f}$  could differ from  $f$  by more.
- We lower-bound uncertainty of the best possible emulator of  $f$ , under optimistic assumptions about the regularity of  $f$ .
- maximum potential error is infinite unless  $f$  has more regularity than continuity.



Let  $K \equiv K(f)$  and  $\hat{K} \equiv K(f|_X)$ . Because  $X \subset [0, 1]^p$ ,  $\hat{K} \leq K$ .



Dotted line is tangent to  $f$  where  $f$  attains its Lipschitz constant: slope  $K$ . The dashed line is the steepest line that intersects any pair of observations: slope  $\hat{K} \leq K$ .

## More notation

$$\mathcal{F}_\kappa \equiv \mathcal{F}_\kappa(f|_X)$$

and

$$\mathcal{E}_\kappa(\hat{f}) \equiv \mathcal{E}(\hat{f}, \mathcal{F}_\kappa).$$

radius of  $\mathcal{F} \subset \mathcal{C}[0, 1]^p$  is

$$r(\mathcal{F}) \equiv \frac{1}{2} \sup \{ \|g - h\|_\infty : g, h \in \mathcal{F} \}.$$

$$\mathcal{E}_\kappa(\hat{f}) \geq r(\mathcal{F}_\kappa). \quad (2)$$

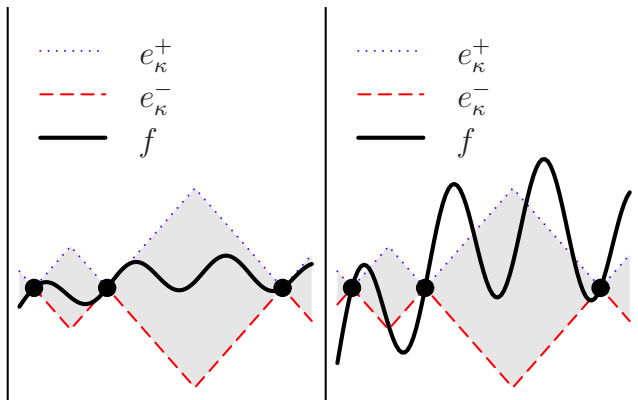
Equality holds for the emulator that “splits the difference”:

$$f_\kappa^*(w) \equiv \frac{1}{2} \left[ \inf_{g \in \mathcal{F}_\kappa} g(w) + \sup_{g \in \mathcal{F}_\kappa} g(w) \right]$$

That is, for all emulators  $\hat{f}$  that agree with  $f$  on  $\mathcal{X}$ ,

$$\mathcal{E}_\kappa(\hat{f}) \geq \mathcal{E}_\kappa(\hat{f}_\kappa^*) \equiv \mathcal{E}_\kappa^* :$$

$f_\kappa^*$  is a minimax (over  $f \in \mathcal{F}_\kappa$ ) for infinity-norm error.



$\hat{K} = 0$ ; optimal interpolant  $f_\kappa^*$  is constant. Left panel:  $\kappa = K$ .  
Right panel:  $\kappa < K$ . If  $\kappa \geq K$  then  $e_\kappa^- \leq f \leq e_\kappa^+$ , and,  
equivalently,  $f \in \mathcal{F}_\kappa$ .

Define

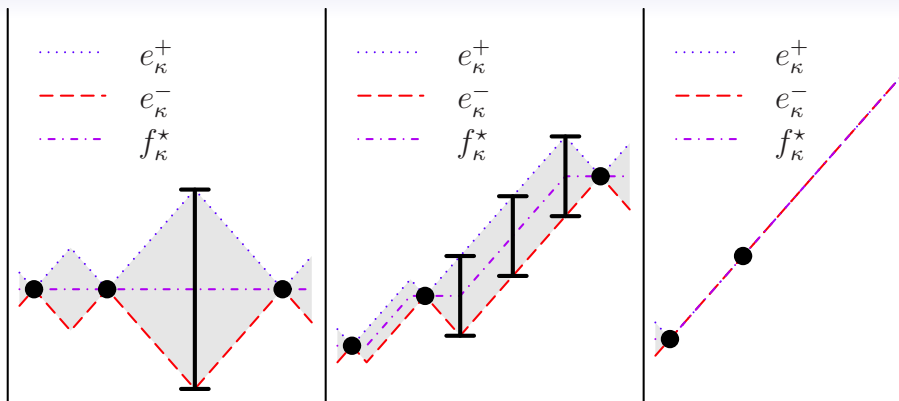
$$e_{\kappa}^{+}(w) \equiv e_{f, X, \kappa}^{+}(w) \equiv \min_{x \in X} [f(x) + \kappa d(x, w)],$$

$$e_{\kappa}^{-}(w) \equiv e_{f, X, \kappa}^{-}(w) \equiv \max_{x \in X} [f(x) - \kappa d(x, w)],$$

and

$$e_{\kappa}^{*}(w) \equiv e_{f, X, \kappa}^{*}(w) \equiv \frac{1}{2} \left[ e_{f, X, \kappa}^{+}(w) - e_{f, X, \kappa}^{-}(w) \right].$$

$e_{\kappa}^{*}(w)$  is minimax error at  $w$ : smallest (across emulators  $\hat{f}$ ) maximum (across functions  $g$ ) error at the point  $w \in [0, 1]^p$  is  $e_{\kappa}^{*}(w)$ .



Black error bars are twice the maximum potential error over  $\mathcal{F}_{\kappa}$ . The succession of panels shows that as the slope between observations approaches  $\kappa$ ,  $e^{*}(w)$  approaches 0 for points  $w$  between observations, and the maximum potential error over  $\mathcal{F}_{\kappa}$  decreases.

## Bounds on the number of observations

Fix “tolerable error”  $\epsilon > 0$

If  $\left\| \hat{f}|_A - g|_A \right\|_{\infty} \leq \epsilon$ , then  $\hat{f}$   $\epsilon$ -approximates  $g$  on  $A$ . If

$A = \text{dom}(g)$ , then  $\hat{f}$   $\epsilon$ -approximates  $g$ .

If  $\mathcal{F}$  is a non-empty class of functions with common domain  $D$ , then  $\hat{f}$   $\epsilon$ -approximates  $\mathcal{F}$  on  $A \subset D$  if  $\forall g \in \mathcal{F}$ ,  $\hat{f}$   $\epsilon$ -approximates  $g$  on  $A$ . If  $A = D$ , then  $\hat{f}$   $\epsilon$ -approximates  $\mathcal{F}$ .

## $\epsilon$ -approximates

$\hat{f}$   $\epsilon$ -approximates  $\mathcal{F}$  if and only if the maximum potential error of  $\hat{f}$  on  $\mathcal{F}$  does not exceed  $\epsilon$ .

Since  $\hat{K}$  is the observed variation of  $f$  on  $\mathcal{X}$ , a useful value of  $\epsilon$  would typically be much smaller than  $\hat{K}$ . (Otherwise, we might just as well take  $\hat{f}$  to be a constant.)



For fixed  $\epsilon > 0$ , and  $Y \subset \text{dom}(f)$ ,  $Y$  is  $\epsilon$ -adequate for  $f$  on  $A$  if  $f_K^*$   $\epsilon$ -approximates  $\mathcal{F}_K(f|_Y)$  on  $A$ . If  $A = \text{dom}(f)$ , then  $Y$  is  $\epsilon$ -adequate for  $f$ .

$B(x, \delta)$ : open ball in  $\mathbb{R}^p$  centered at  $x$  with radius  $\delta$ .

$$N_f \equiv \min\{\#Y : Y \text{ is } \epsilon\text{-adequate for } f\},$$

where  $\#Y$  is the cardinality of  $Y$ .

The minimum potential computational burden is

$$M \equiv \max\{N_g : g \in \mathcal{F}_K\}.$$

Over all experimental designs  $Y$ ,  $M$  is the smallest number of data to guarantee that maximum error of the best emulator based on those data is not larger than  $\epsilon$ .

## Upper bound on $N_f$

For each  $x \in X$ ,  $f_K^*$   $\epsilon$ -approximates  $\mathcal{F}_K(f|_K)$  on (at least)  $B(x, \epsilon/K)$ . Thus,  $f_K^*$   $\epsilon$ -approximates  $\mathcal{F}_K$  on  $\bigcup_{x \in X} B(x, \epsilon/K)$ . Hence, the cardinality of any  $Y \subset [0, 1]^p$  for which

$$V \equiv \left\{ B\left(x, \frac{\epsilon}{K}\right) : x \in Y \right\} \supset [0, 1]^p$$

is an upper bound on  $N_f$ .

In  $\ell_\infty$ ,  $[0, 1]^p$  can be covered by  $\left\lceil \frac{K^+}{2\epsilon} \right\rceil^p$  balls of radius  $\epsilon/K^+$ .

## Lower bound on $N_f$

- Can happen that  $f_{\hat{K}}^*$   $\epsilon$ -approximates  $\mathcal{F}_K$  on regions of the domain not contained in  $\cup_{x \in X} B(x, \epsilon/K)$ .
- If  $f$  varies on  $X$ , then for a function  $g$  to agree with  $f$  at the observations requires  $g$  to vary too.
- Fitting the data “spends” some of  $g$ ’s Lipschitz constant: can’t get as far away from  $f$  as it could if  $f_X$  were constant.
- Can quantify to find lower bounds for  $M$ .

Define  $\bar{\gamma} \equiv \arg \min_{\gamma \in \mathbb{R}} \sum_{x \in X} |f(x) - \gamma|^p$ .

Let  $X^+ \equiv \{x \in X : f(x) \geq \bar{\gamma}\}$  and let  $X^- \equiv \{x \in X : f(x) < \bar{\gamma}\}$ .

Let

$$Q_+ \equiv \bigcup_{x \in X^+} \left\{ B \left( x, \frac{f(x) - \bar{\gamma}}{\hat{K}} \right) \cap [0, 1]^p \right\}$$

and

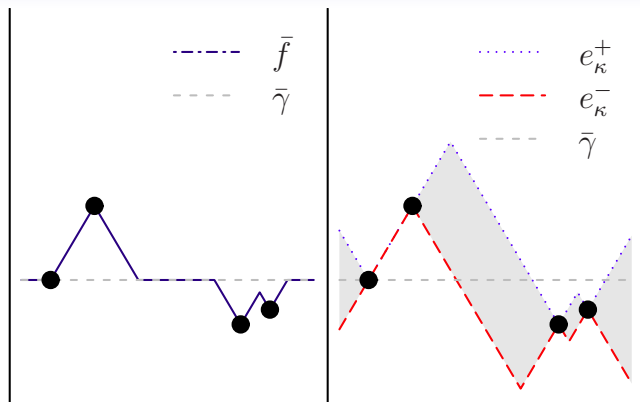
$$Q_- \equiv \bigcup_{x \in X^-} \left\{ B \left( x, \frac{\bar{\gamma} - f(x)}{\hat{K}} \right) \cap [0, 1]^p \right\}.$$

Then  $Q_+ \cap Q_- = \emptyset$

Define

$$\bar{f} : [0, 1]^p \rightarrow \mathbb{R}$$

$$w \mapsto \begin{cases} e_{\hat{K}}^-(w), & w \in Q_+ \\ e_{\hat{K}}^+(w), & w \in Q_- \\ \bar{\gamma}, & \text{otherwise.} \end{cases}$$



$\bar{f}$  (left panel) is comprised of segments of  $e_{\hat{\kappa}}^+$ ,  $e_{\hat{\kappa}}^-$  and the constant  $\bar{\gamma}$  (right panel).  $\bar{f}$  constant over roughly half of the domain. No function between  $e_{\hat{\kappa}}^-$  and  $e_{\hat{\kappa}}^+$  (inclusive) is constant over a larger fraction of the domain.

## Result 1

$\mu$ : Lebesgue measure.  $\bar{Q} \equiv [0, 1]^p \setminus (Q_+ \cup Q_-)$ .

$$\mu(\bar{Q}) \geq 1 - \sum_{x \in X} \mu\left(B\left(x, |f(x) - \bar{\gamma}|/\hat{K}\right)\right).$$

$C_2 \equiv \frac{\pi^{p/2}}{\Gamma(p/2+1)}$  and  $C_\infty \equiv 2^p$ . For  $q \in \{2, \infty\}$ ,

$$\mu(\bar{Q}) \geq 1 - C_q \sum_{x \in X} \left(|f(x) - \bar{\gamma}|/\hat{K}\right)^p.$$

If  $\exists x \in X$  for which  $\{x\}$  is  $\epsilon$ -adequate for  $f$  on  $A \subset \bar{Q}$ , then  $\mu(A) \leq \mu(B(0, \epsilon/\hat{K}))$ .

$$M \geq \left[ \frac{\mu(\bar{Q})}{\mu(B(0, \epsilon/\hat{K}))} \right] \geq \left[ \epsilon^{-p} \left[ \frac{\hat{K}^p}{C_q} - \sum_{x \in X} |f(x) - \bar{\gamma}|^p \right] \right]. \quad (3)$$

## PCMDI

- Program for Climate Model Diagnosis & Intercomparison (PCMDI) at LLNL: 1154 climate simulations using the Community Atmosphere Model (CAM).
- $p = 21$  parameters scaled so that  $[0, 1]$  has all plausible values.
- $f$  is global average upwelling longwave flux (FLUT) approximately 50 years in the future.
- Each run took several days on a supercomputer.
- PCMDI used several approaches to choose  $X \subset [0, 1]^p$ : Latin hypercube, one-at-a-time, and random-walk multiple-one-at-a-time.
- 1154 simulations total.



$\bar{\gamma} = 232.77$ ;  $\hat{K} = 14.20$  for  $q = 2$ :

$$M \geq \left[ \epsilon^{-21} \left[ \frac{1.57 \times 10^{24}}{0.0038} - 6.81 \times 10^{24} \right] \right] > \epsilon^{-21} \times 10^{26}.$$

If  $\epsilon$  is 1% of  $\hat{K}$ , then  $M \geq 10^{43}$ .

Even if  $\epsilon$  is 50% of  $\hat{K}$ ,  $M > 10^8$ . For  $q = \infty$ ,  $\hat{K} = 34.68$ ; in that case

$$M \geq \left[ \epsilon^{-21} \left[ \frac{2.19 \times 10^{32}}{2^{21}} - 6.81 \times 10^{25} \right] \right] > \epsilon^{-21} \times 10^{25}.$$

## Lower bounds on maximum potential error

- Two lower bounds on the maximum potential error  $\mathcal{E}_K^*$  for fixed  $\mathcal{X}$ : absolute, and as a fraction of unknown  $K$ .
- Bound as fraction of  $K$  shows that when a statistic—calculable from the observations—exceeds a calculable threshold, the maximum potential error is no less than the maximum potential error from one observation at the centroid.
- Observing  $f$  for all  $x \in \mathcal{X}$  was wasteful: one observation would have been better.
- For LLNL CAM runs, both bounds are large.

## Result 2

### Theorem

$$\mathcal{E}_K(\hat{f}) \geq \sup e_{\hat{K}}^*.$$

$\sup e_{\hat{K}}^*$ , a statistic calculable from data  $f|_{\mathcal{X}}$ , is a lower bound on the maximum potential error for any emulator  $\hat{f}$  based on the observations  $f|_{\mathcal{X}}$ .

## Result 3: Scaling Lemma

### Lemma

For any  $\lambda$ , if  $\sup e_{\hat{K}}^* \geq \lambda \hat{K}$ , then  $\mathcal{E}_K(\hat{f}) \geq \lambda K$ .

## Maximum potential error from 1 observation

Work in  $\ell_\infty$ :  $d(v, w) = \|v - w\|_\infty$ .

$z \equiv (1/2, \dots, 1/2)$ , the centroid of  $[0, 1]^p$ .

$\hat{g} \in \mathcal{F}_\infty(f|_{\{z\}})$  is constant function  $\hat{g}(w) \equiv f(z)$ ,  $\forall w \in [0, 1]^p$ .

$\ell_\infty$  distance from  $z$  to any boundary point of  $[0, 1]^p$  is  $1/2$ , so

$$\mathcal{E}_K(\hat{g}, \mathcal{F}_K(f|_{\{z\}})) = \frac{K}{2}.$$

## Result 4

Let  $W \subset [0, 1]^P$  be finite and  $c \in \mathbb{R}$ . Suppose  $f|_W = c$ . Let  $\hat{h} \in \mathcal{F}_\infty(f|_W)$ . By examining the corners of the domain, it follows that if  $|W| < 2^P$ ,

$$\mathcal{E}_K(\hat{h}, \mathcal{F}_K(f|_W)) \geq \frac{K}{2}.$$

If  $f$  is constant on  $W$ , any emulator based on fewer than  $2^P$  observations of  $f$  will have at least  $K/2$  maximum potential error.

Making  $2^P$  observations of  $f$  is intractable for CAM and many other applications.

## Result 5

### Theorem

If  $\sup e_{\hat{K}}^* \geq \hat{K}/2$ , then

$$\mathcal{E}_K(\hat{f}) = \mathcal{E}_K(\hat{f}, \mathcal{F}_K(f|_X)) \geq \frac{K}{2} \geq \mathcal{E}_K(\hat{g}, \mathcal{F}_K(f|_{\{z\}})).$$

If  $\sup e_{\hat{K}}^* \geq \hat{K}/2$ , no  $\hat{f}$  based on  $f|_X$  has smaller maximum potential error than the constant emulator based on one observation.

# CAM: Upper bound from non-adjacent corners in $\ell_\infty$ .

## Theorem

$$\sup e_{\hat{K}}^* \leq \frac{1}{2} \left\{ \min_{x \in X} [f(x) + \hat{K} \tilde{d}(x)] - \max_{x \in X} [f(x) - \hat{K} \tilde{d}(x)] \right\}.$$

$\sup e_{\hat{K}}^* \leq 20.95$  for the CAM dataset.



## CAM: Lower bounds from corners in $\ell_\infty$ .

Clearly

$$\sup e_{\hat{K}}^* \geq \max \left\{ e_{\hat{K}}^*(w) : \forall w \in \{0, 1\}^P \right\}.$$

Essentially sharp for the CAM dataset.

Divide  $[0, 1]^P$  into  $2^P$  hypercubes  $\{R_i\}_{i=1}^{2^P}$  with edge-length  $1/2$ , disjoint interiors, each containing a different corner of  $[0, 1]^P$

Because  $X$  contains only 1154 points, most  $R_i$  do not contain any  $x \in X$ .

## The bounds are tight for CAM

For the CAM dataset, one corner  $r_j$  attains  $e_{\hat{K}}^*(r_j) = 20.95$ .

So,  $e_{\hat{K}}^*$  attains the upper bound established in the previous section, and  $\sup e_{\hat{K}}^* = 20.95$ .

## Implications for CAM

Because  $\sup e_{\hat{K}}^* = 20.95 \geq 17.34 = \hat{K}/2$ ,  $\mathcal{E}_K(\hat{f}) \geq K/2$  for any interpolation  $\hat{f}$ .

Maximum potential error would have been no greater had we just observed  $f$  once, at  $z$ , and predicted  $\hat{f}(w) = f(z)$  for all  $w \in [0, 1]^P$ .

## Extensions

- Looked at maximum uncertainty over all  $w \in [0, 1]^P$ .
- Important in some applications; in others, maybe less interesting than the fraction of  $[0, 1]^P$  where uncertainty is large.
- Can estimate the fraction of  $[0, 1]^P$  for which  $e^* \geq \epsilon > 0$  by sampling.
- Draw  $w \in [0, 1]^P$  at random and evaluate  $e^*$  at each selected point.
- Yields binomial lower confidence bounds for the fraction of  $[0, 1]^P$  where uncertainty is large, and confidence bounds for quantiles of the potential error.

## CAM: bounds on percentiles of error

| norm      | 95% lower confidence bound |        |                |         |
|-----------|----------------------------|--------|----------------|---------|
|           | lower quartile             | median | upper quartile | average |
| Euclidean | 1.454                      | 1.596  | 1.731          | 1.595   |
| supremum  | 0.649                      | 0.717  | 0.782          | 0.715   |

Error of minimax emulator  $f_{\hat{K}}^*$  of CAM model from 1154 LLNL observations. Column 1: metric  $d$  used to define the Lipschitz constant. Columns 2–4: Binomial lower confidence bounds for quartiles of the pointwise error. Column 5: 95% lower confidence bound for the integral of the pointwise error over the entire domain  $[0, 1]^P$ . Columns 2–5 are expressed as multiple of  $\hat{K}/2$ . Based on 10,000 random samples.

## Conclusions

- In some problems, every emulator based on any tractable number of observations of  $f$  has large maximum potential error (and the potential error is large over much of the domain), even if  $f$  is no less regular than it is observed to be.
- Can find sufficient conditions under which all emulators are potentially substantially incorrect.
- Conditions depend only on the observed values of  $f$ ; can be computed from the same observations used to train an emulator, at small incremental cost.
- Conditions are sufficient but not necessary:  $f$  could be less regular than any finite set of observations reveals it to be.
- It is not possible to give necessary conditions that depend only on the data.
- Conditions seem to hold for problems with large societal interest.

- Reducing the potential error of emulators in HEB problems requires either more information about  $f$  (knowledge, not merely assumptions), or changing the measure of uncertainty—changing the scientific question.
- Both tactics are application-specific: the underlying science dictates the conditions that actually hold for  $f$  and the senses in which it is useful to approximate  $f$ .
- Not clear that emulators help address the most important questions.
- Approximating  $f$  pointwise rarely ultimate goal; most properties of  $f$  are nuisance parameters.
- Important questions about  $f$  might be answered more directly.
- Some research questions cannot be answered through simulation at present.
- Employing complex emulators and massive computational is a distraction.